

2A, 600V N-CHANNEL MOSFET

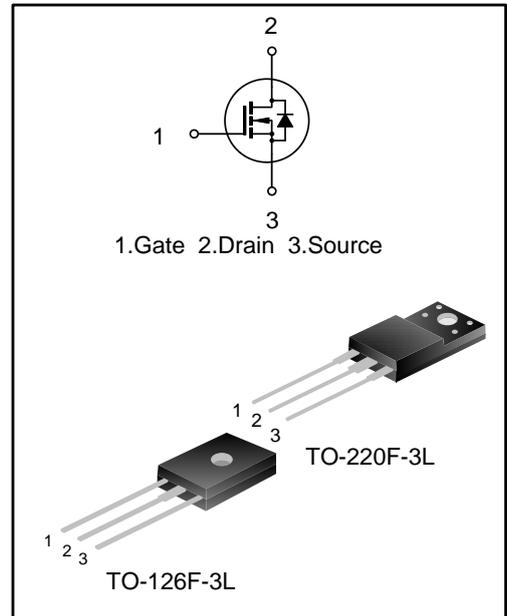
GENERAL DESCRIPTION

SVF2N60NF(F) is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell™ high-voltage planar VDMOS technology. The improved process and cell structure have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are widely used in AC-DC power supplies, DC-DC converters and H-bridge PWM motor drivers.

FEATURES

- ◆ 2A,600V, $R_{DS(on)(typ.)}=3.7\Omega@V_{GS}=10V$
- ◆ Low gate charge
- ◆ Low C_{rss}
- ◆ Fast switching
- ◆ Improved dv/dt capability



ORDERING INFORMATION

Part No.	Package Type	Marking	Hazardous substance control	Packing Type
SVF2N60NF	TO-126F-3L	SVF2N60NF	Pb free	Tube
SVF2N60F	TO-220F-3L	SVF2N60F	Pb free	Tube

ABSOLUTE MAXIMUM RATINGS (T_A=25°C UNLESS OTHERWISE NOTED)

Characteristics	Symbol	Ratings		Unit
		SVF2N60NF	SVF2N60F	
Drain-Source Voltage	V _{DS}	600		V
Gate-Source Voltage	V _{GS}	±30		V
Drain Current	I _D	T _C =25°C		A
		T _C =100°C		
Drain Current Pulsed	I _{DM}	8.0		A
Power Dissipation(T _C =25°C) -Derate above 25°C	P _D	16	23	W
		0.13	0.18	W/°C
Single Pulsed Avalanche Energy(Note1)	E _{AS}	115		mJ
Operation Junction Temperature Range	T _J	-55~+150		°C
Storage Temperature Range	T _{stg}	-55~+150		°C

THERMAL CHARACTERISTICS

Characteristics	Symbol	Ratings		Unit
		SVF2N60NF	SVF2N60F	
Thermal Resistance, Junction-to-Case	R _{θJC}	7.81	5.56	°C/W
Thermal Resistance, Junction-to-Ambient	R _{θJA}	120	62.5	°C/W

ELECTRICAL CHARACTERISTICS (T_C=25°C UNLESS OTHERWISE NOTED)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	600	--	--	V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =600V, V _{GS} =0V	--	--	1.0	μA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =±30V, V _{DS} =0V	--	--	±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{GS} = V _{DS} , I _D =250μA	2.0	--	4.0	V
Static Drain- Source On State Resistance	R _{DS(on)}	V _{GS} =10V, I _D =1.0A	--	3.7	4.2	Ω
Input Capacitance	R _g	f=1.0MHz	--	3.5	--	Ω
Input Capacitance	C _{iSS}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	--	233	--	pF
Output Capacitance	C _{oss}		--	32	--	
Reverse Transfer Capacitance	C _{rSS}		--	2.8	--	
Turn-on Delay Time	t _{d(on)}	V _{DD} =300V, I _D =2.0A, R _G =25Ω (Note 2,3)	--	8.9	--	ns
Turn-on Rise Time	t _r		--	23	--	
Turn-off Delay Time	t _{d(off)}		--	23	--	
Turn-off Fall Time	t _f		--	25	--	
Total Gate Charge	Q _g	V _{DS} =480V, I _D =2.0A, V _{GS} =10V (Note 2,3)	--	8.2	--	nC
Gate-Source Charge	Q _{gs}		--	1.6	--	
Gate-Drain Charge	Q _{gd}		--	4.4	--	

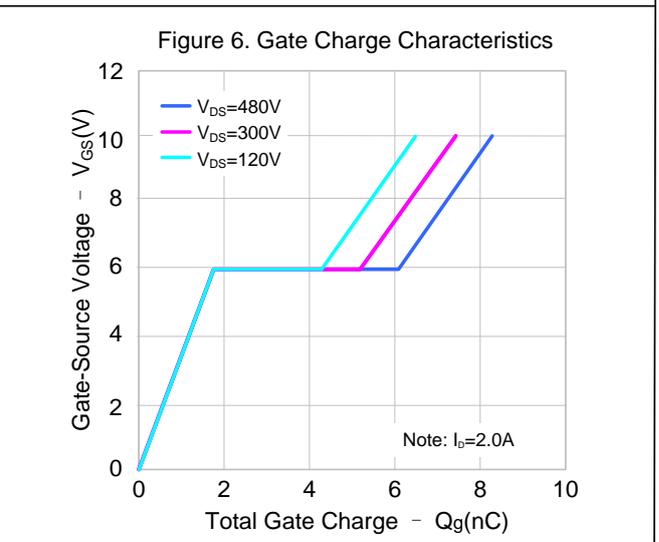
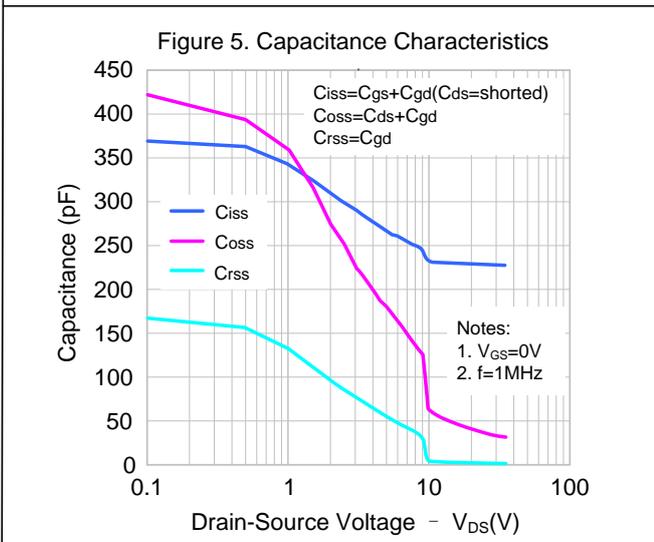
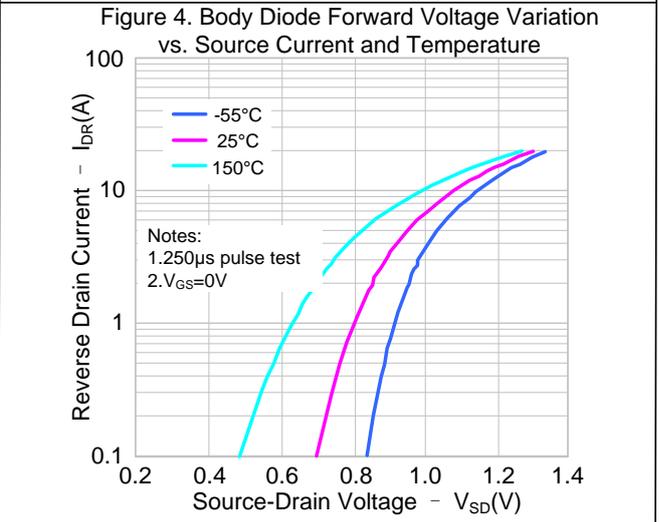
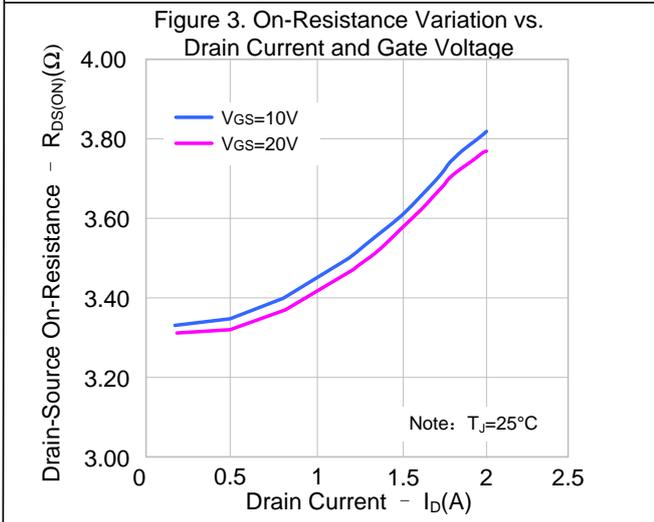
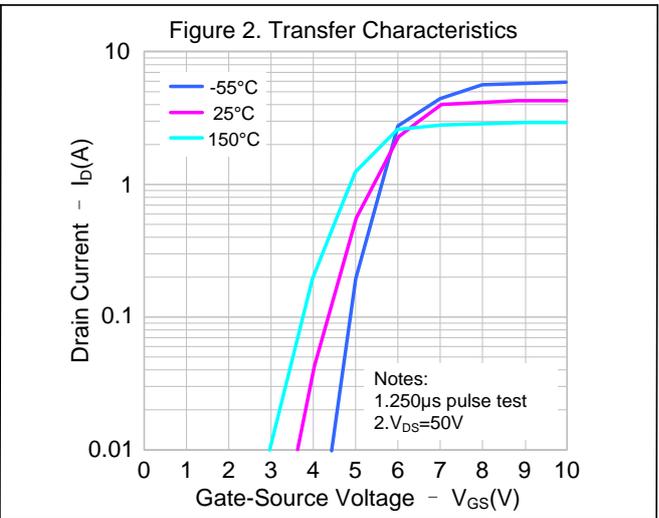
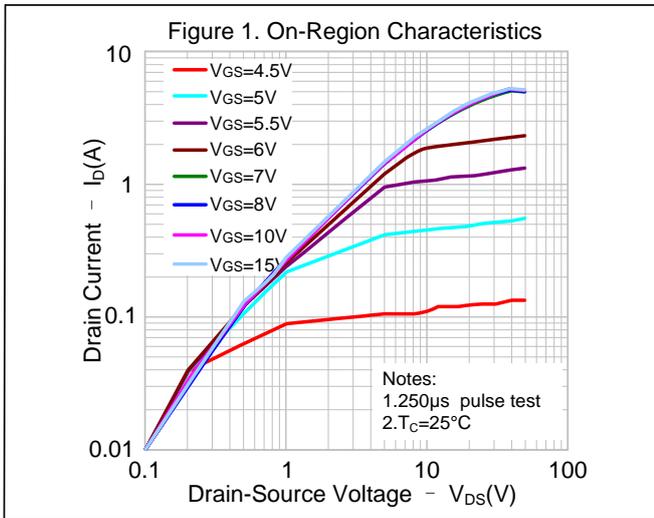
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_S	Integral Reverse P-N Junction	--	--	2.0	A
Pulsed Source Current	I_{SM}	Diode in the MOSFET	--	--	8.0	
Diode Forward Voltage	V_{SD}	$I_S=2.0A, V_{GS}=0V$	--	--	1.4	V
Reverse Recovery Time	T_{rr}	$I_S=2.0A, V_{GS}=0V,$	--	326	--	ns
Reverse Recovery Charge	Q_{rr}	$di_F/dt=100A/\mu s$	--	0.9	--	μC

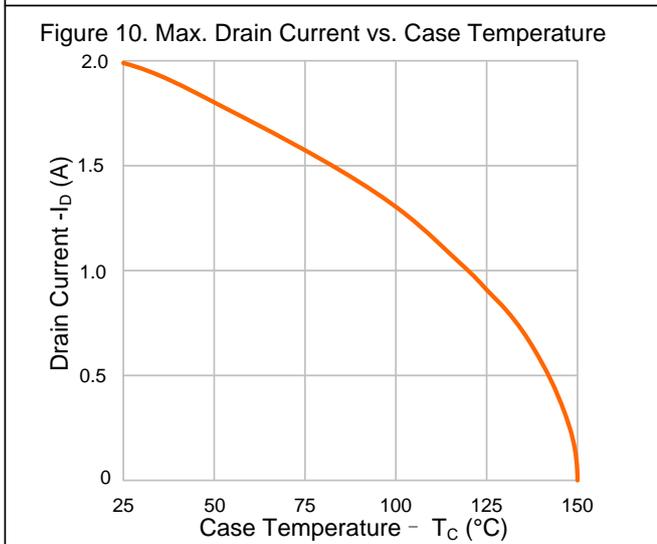
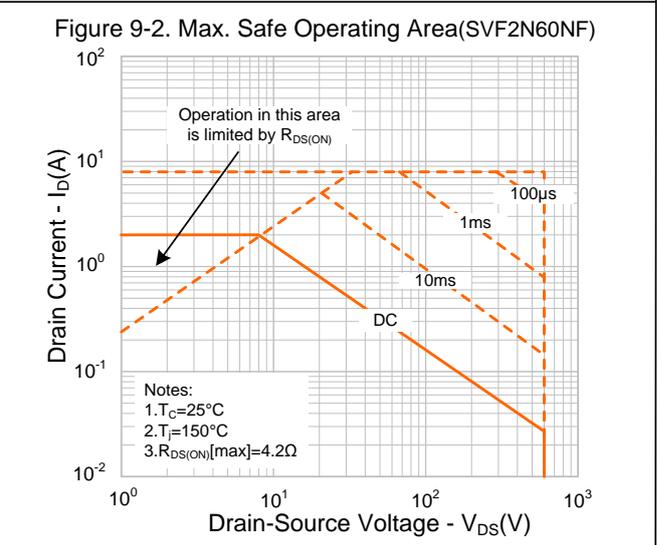
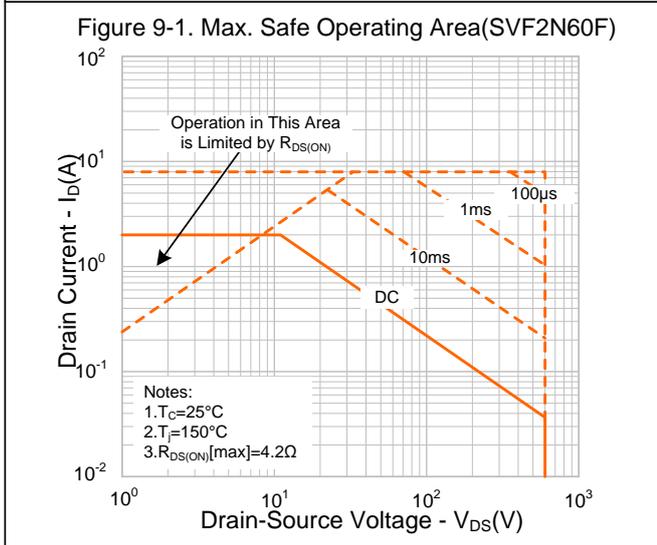
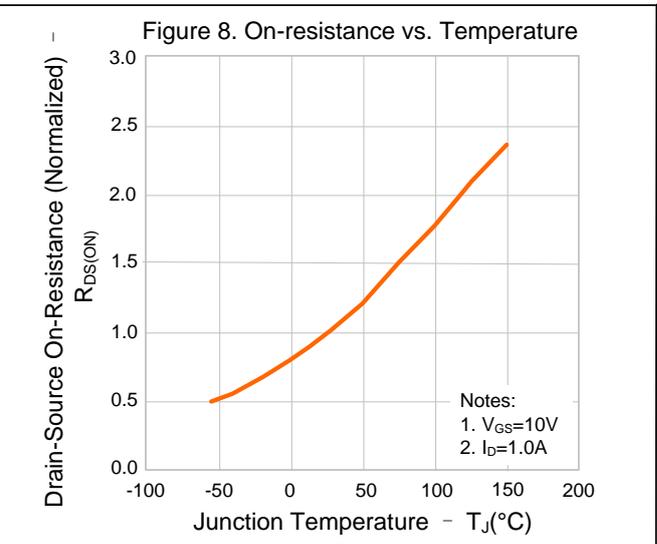
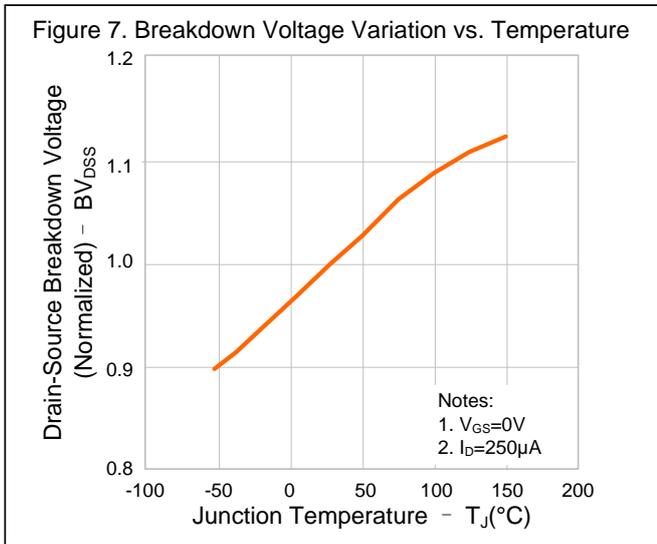
Notes:

1. $L=30mH, I_{AS}=2.52A, V_{DD}=100V, R_G=25\Omega$, starting $T_J=25^\circ C$;
2. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$;
3. Essentially independent of operating temperature.

TYPICAL CHARACTERISTICS

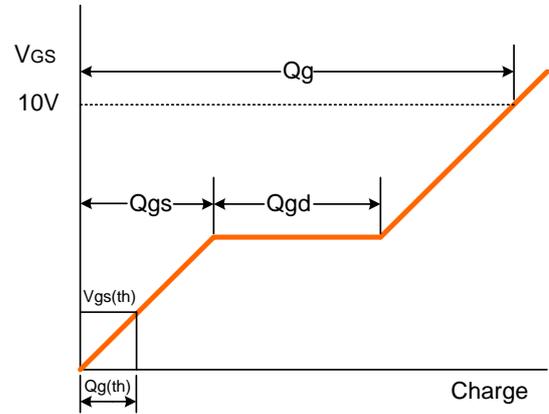
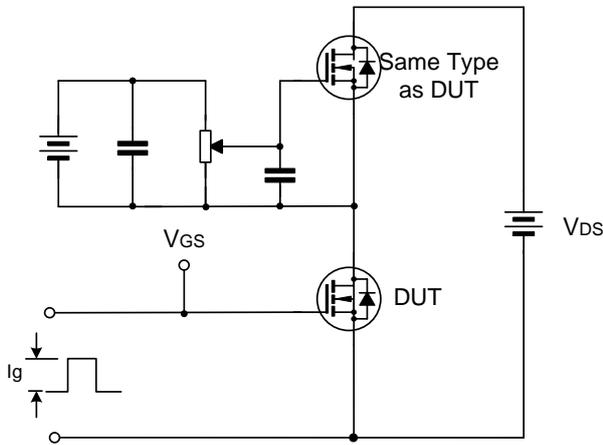


TYPICAL CHARACTERISTICS(CONTINUED)

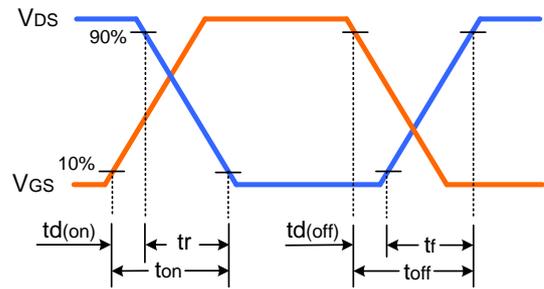
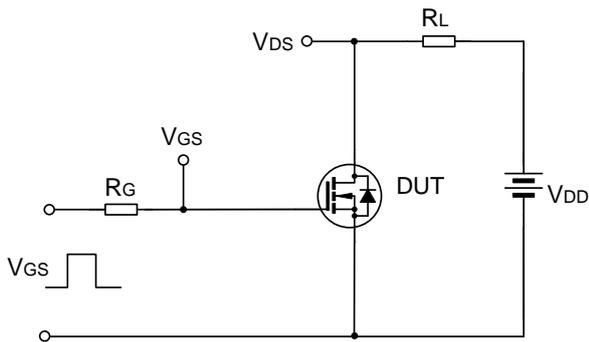


TYPICAL TEST CIRCUIT

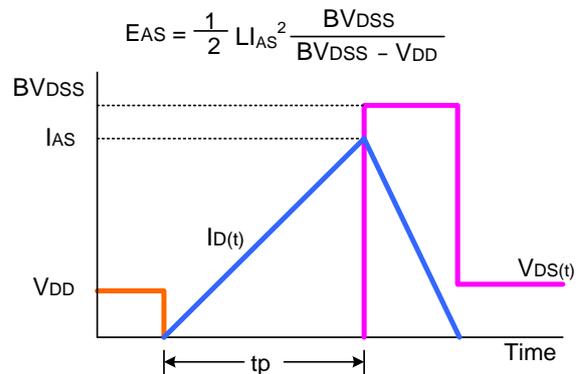
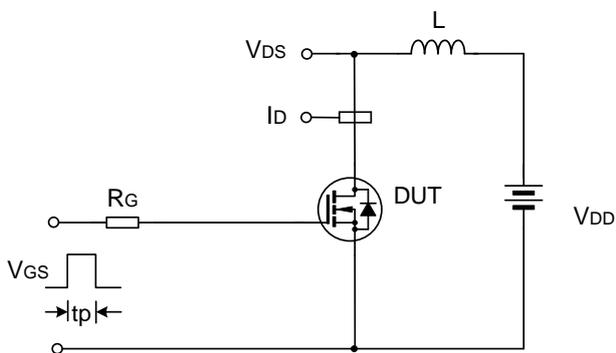
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform

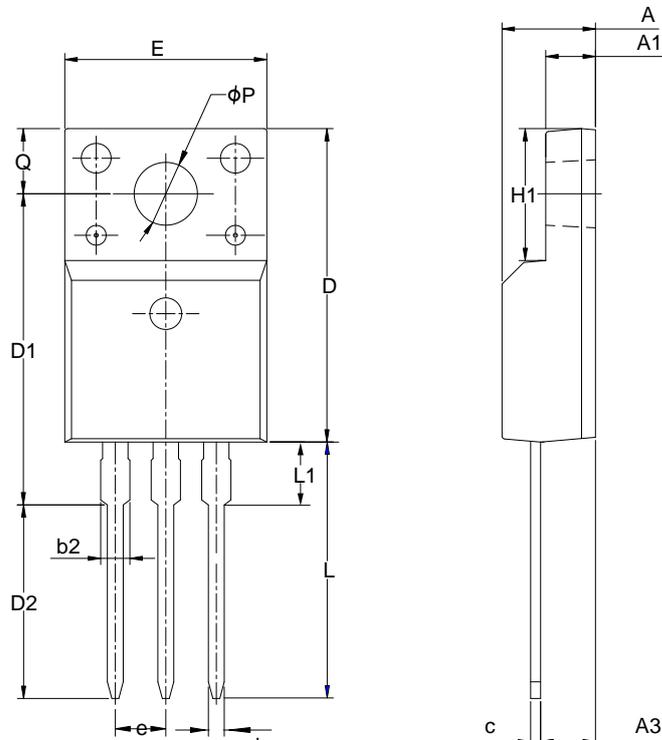


Unclamped Inductive Switching Test Circuit & Waveform



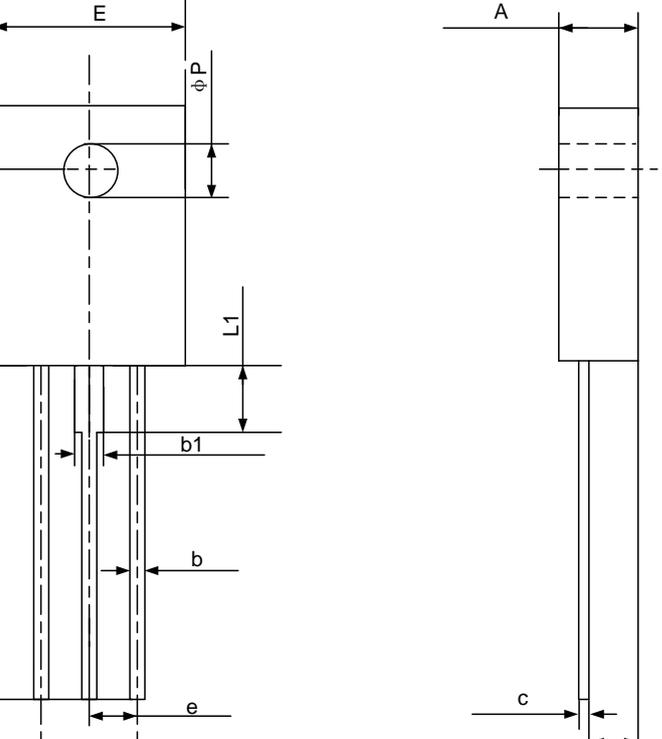
PACKAGE OUTLINE

TO-220F-3L UNIT: mm



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	4.42	4.70	5.02
A1	2.30	2.54	2.80
A3	2.50	2.76	3.10
b	0.70	0.80	0.90
b2	—	—	1.47
c	0.35	0.50	0.65
D	15.25	15.87	16.25
D1	15.30	15.75	16.30
D2	9.30	9.80	10.30
E	9.73	10.16	10.36
e	2.54BSC		
H1	6.40	6.68	7.00
L	12.48	12.98	13.48
L1	—	—	3.50
φP	3.00	3.18	3.40
Q	3.05	3.30	3.55

TO-126F-3L UNIT: mm



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	3.10	3.20	3.30
A1	1.90	2.00	2.10
b	0.66	0.76	0.86
b1	—	1.27	—
c	0.40	0.50	0.60
D	10.80	11.00	11.20
E	7.80	8.00	8.20
e	2.10	2.30	2.50
e1	4.40	4.60	4.80
L	14.50	15.00	15.50
L1	—	1.90	—
φP	2.95	3.05	3.15
Q	3.70	3.80	3.90

Important notice :

1. The instructions are subject to change without notice!
2. Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current. Please read the instructions carefully before using our products, including the circuit operation precautions.
3. Our products are consumer electronic products or the other civil electronic products.
4. When using our products, please do not exceed the maximum rating of the products, otherwise the reliability of the whole machine will be affected. There is a certain possibility of failure or malfunction of any semiconductor product under specific conditions. The buyer is responsible for complying with safety standards and taking safety measures when using our products for system design, sample and whole machine manufacturing, so as to avoid potential failure risk that may cause personal injury or property loss.
5. It is strongly recommended to identify the trademark when buying our products. Please contact us if there is any question.
6. Product promotion is endless, our company will wholeheartedly provide customers with better products!
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Part No.:	SVF2N60NF(F)	Document Type:	Datasheet
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Rev.: 3.7

Revision History:

1. Remove SVF2N60ND (TO-252-2L)、SVF2N60M (TO-251D-3L) and SVF2N60MJ (TO-251J-3L) package
 2. Update the specification template
 3. Update the main notes
-

Rev.: 3.6

Revision History:

1. Modify Electrical schematic and TYPICAL TEST CIRCUIT
 2. Modify some errors
-

Rev.: 3.5

Revision History:

1. Delete the package outline of TO-220-3L
 2. Delete the package outline of TO-126-3L
-

Rev.: 3.4

Revision History:

1. Update the package outline of TO-251J-3L
 2. Delete the package outline of TO-220F-3L(2)
-

Rev.: 3.3

Revision History:

1. Update characteristics
-

Rev.: 3.2

Revision History:

1. Modify the Ordering information
-

Rev.: 3.1

Revision History:

1. Modify the package outline of TO-126-3L
 2. Modify the package outline of TO-251 D -3L
-

Rev.: 3.0

Revision History:

1. Modify the package information of TO-220-3L

Rev.: 2.9

Revision History:

1. Modify the package of TO-220F-3L; Modify the package of TO-252-2L;

Rev.: 2.8

Revision History:

1. Modify the thermal characteristics

Rev.: 2.7

Revision History:

1. Modify the note 1

Rev.: 2.6

Revision History:

1. Add the pin No.

Rev.: 2.5

Revision History:

1. Modify the package outline of TO-251J-3L

Rev.: 2.4

Revision History:

1. Modify the ordering information

Rev.: 2.3

Revision History:

1. Modify the package outline of TO-126-3L
1. Change the schematic diagram of MOS

Rev.: 2.1

Revision History:

1. Modify the package outline of TO-251D-3L; Add the value of forward transconductance

Rev.: 2.0

Revision History:

1. Add the halogen free information of SVF2N60M

Rev.: 1.9

Revision History:

1. Modify "PACKAGE OUTLINE"

Rev.: 1.8

Revision History:

1. Add the package of TO-126-3L(2)

Rev.: 1.7

Revision History:

1. Add the package of TO-126F-3L

Rev.: 1.6

Revision History:

1. Modify the values of T_{rr} and Q_{rr} ; Update the package outline of TO-251D-3L

Rev.: 1.5

Revision History:

1. Add the halogen free information of SVF2N60F
-

Rev.: 1.4

Revision History:

1. Delete the package of TO-251-3L
-

Rev.: 1.3

Revision History:

1. Modify "PACKAGE OUTLINE"
-

Rev.: 1.2

Revision History:

1. Add the package of TO-251D-3L, TO-251J-3L, TO-126-3L
-

Rev.: 1.1

Revision History:

1. Modify "TYPICAL CHARACTERISTICS", "PACKAGE OUTLINE", the template of Datasheet
-

Rev.: 1.0

Revision History:

1. Original
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